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Radiation Effects of Advanced Electronic Devices and Circuits, 2nd Edition

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Message from the Guest Editors

Dear Colleagues,

Research on the effects of radiation on advanced electronic devices and integrated circuits has increased rapidly over the last few years, resulting in many interesting approaches to the modeling of radiation effects and the design of advanced radiation-hardened electronic devices and integrated circuits.

This Special Issue is to highlight emerging applications and address recent breakthroughs in modeling radiation effects in advanced electronic devices and integrated circuits. The topics of interest include, but are not limited to:

- Basic mechanisms, Compact modeling of radiation effects in advanced electronic devices, integrated circuits and novel devices.
- Radiation hardening and fault tolerance for advanced electronic devices, integrated circuits and novel devices.
- Radiation environment influence: space, atmospheric, terrestrial and artificial.
- Radiation effect characterization and radiation hardness assurance testing.
- New developments of interest to the radiation effect community.

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Guest Editors









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Message from the Editor-in-Chief

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